

Table of Contents

Guest Editorial	
M. Zinke Allmang, E.D. Williams, H. Iwasaki	1
Nucleation, Growth and Coarsening in Phase-Separating Systems	
C. Sagui, D. Stinson O'Gorman, M. Grant	3
Transition of Growth Mode in Electrochemical Deposition of Copper: Atomic Force Microscopy Analysis and Simulation	
A. Iwamoto, K. Sudoh, T. Yoshinobu, H. Iwasaki	9
The Dynamics of Steps on Vicinal Surfaces During Reconstruction-Driven Faceting	
H.-C. Jeong, J.D. Weeks	17
The Evolution of Rotating Silicon Surfaces During Ion Bombardment	
G.R. Carlow	31
Scanning Probe Microscopy of Semiconductor Heterostructures	
C.K. Shih, S. Gwo, A.R. Smith, K.-J. Chao, G. Guttroff, J.W. Keto	43
Application of Scanning Tunneling/Atomic Force Microscope Nano-Oxidation Process to Room Temperature Operated Single Electron Transistor and Other Devices	
K. Matsumoto	61
Scanning Probe Microscopy Studies of Electrically Active Defects in Lattice Mismatched Films	
J.W.P. Hsu, M.H. Gray, Q. Xu	71
Simulations of Homoepitaxial Growth of Pt(111): Island Shapes and the Growth Mode	
J. Jacobsen, K.W. Jacobsen and J.K. Nørskov	81
Fresnel Projection Microscopy, Theory and Experiment: Electron Microscopy with Nanometer Resolution at 200 Volts	
Vu Thien Binh, V. Semet, S.T. Purcell, F. Feschet	93
Relaxation of Surface Corrugations Below the Roughening Temperature	
M.V.R. Murty, B.H. Cooper	107
Correlation Between Scanning Tunneling Microscopy (STM)-Induced Photon Map and the STM Topography of Nanometer-Size Metal Particles	
R. Nishitani, T. Umeno, A. Kasuya, Y. Nishina	113

Cobalt Grain Growth on Clean Si(100) Surfaces T.D. Lowes, M. Zinke–Allmang	119
Backscattering of Positrons from Solid Targets M. Dapor, A. Miotello	131
A Scanning Force Microscope Combined With a Scanning Electron Microscope for Multidimensional Data Analysis M. Troyon, H.N. Lei, Z. Wang, G. Shang	139
Dislocation Luminescence in Cadmium Telluride H.S. Leipner, J. Schreiber, H. Uniewski, S. Hildebrandt	149
Backscattered Electrons Topographic Mode Problems in the Scanning Electron Microscope D. Kaczmarek	161
The Use of Secondary Ion Velocity Distributions to Analyse Matrix Effects and Concentration Profiles Across ZrO ₂ /Zr Structures P.A.W. van der Heide, B.D. Warr, N.S. McIntyre	171
Backscattering Coefficients for Low Energy Electrons A.M.D. Assa'd, M.M. El Gomati	185
Quadratic Response Theory for the Interaction of Charged Particles with an Electron Gas J.M. Pitarke, I. Campillo	193
Models for Interpreting Scanning Capacitance Microscope Measurements J.F. Marchiando, J.R. Lowney, J.J. Kopanski	205
Three-Dimensional Probe and Surface Reconstruction for Atomic Force Microscopy Using a Deconvolution Algorithm A.A. Bukharaev, N.V. Berdunov, D.V. Ovchinnikov, K.M. Salikhov	225
Scanning Tunneling Microscopy Studies of Phase Transitions in Liquid Crystals M. Rivera Hernandez, M.J. Miles	235
Changes in Surface Stress Measured with an Atomic Force Microscope R. Raiteri, H.-J. Butt, M. Grattarola	243
List of Reviewers for Scanning Microscopy Vol. 12, Number 1, 1998	253